

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10752642	NAKAMURA ET AL.
	Examiner	Art Unit
	CHRIS C CHU	2815

SEARCHED

Class	Subclass	Date	Examiner
257	E21.584, E21.582, E21.174, 758, 751, 762 an 763d	6/30/09	C.C.

SEARCH NOTES

Search Notes	Date	Examiner
Searched in US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; FPRS; and IBM_TDB;	6/30/09	C.C.

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner